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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	21000
Number of Logic Elements/Cells	84000
Total RAM Bits	3833856
Number of I/O	365
Number of Gates	-
Voltage - Supply	1.045V ~ 1.155V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	756-FBGA
Supplier Device Package	756-CABGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5um-85f-7bg756i

Contents

Acronyms in This Document	9
1. General Description	10
1.1. Features	10
2. Architecture	12
2.1. Overview	12
2.2. PFU Blocks	13
2.2.1. Slice	14
2.2.2. Modes of Operation	17
2.3. Routing	18
2.4. Clocking Structure	18
2.4.1. sysCLOCK PLL	18
2.5. Clock Distribution Network	19
2.5.1. Primary Clocks	20
2.5.2. Edge Clock	21
2.6. Clock Dividers	22
2.7. DDRDLL	23
2.8. sysMEM Memory	24
2.8.1. sysMEM Memory Block	24
2.8.2. Bus Size Matching	25
2.8.3. RAM Initialization and ROM Operation	25
2.8.4. Memory Cascading	25
2.8.5. Single, Dual and Pseudo-Dual Port Modes	25
2.8.6. Memory Core Reset	26
2.9. sysDSP™ Slice	26
2.9.1. sysDSP Slice Approach Compared to General DSP	26
2.9.2. sysDSP Slice Architecture Features	27
2.10. Programmable I/O Cells	30
2.11. PIO	32
2.11.1. Input Register Block	32
2.11.2. Output Register Block	33
2.12. Tristate Register Block	34
2.13. DDR Memory Support	35
2.13.1. DQS Grouping for DDR Memory	35
2.13.2. DLL Calibrated DQS Delay and Control Block (DQSBUF)	36
2.14. sysI/O Buffer	38
2.14.1. sysI/O Buffer Banks	38
2.14.2. Typical sysI/O I/O Behavior during Power-up	39
2.14.3. Supported sysI/O Standards	39
2.14.4. On-Chip Programmable Termination	40
2.14.5. Hot Socketing	40
2.15. SERDES and Physical Coding Sublayer	41
2.15.1. SERDES Block	43
2.15.2. PCS	43
2.15.3. SERDES Client Interface Bus	44
2.16. Flexible Dual SERDES Architecture	44
2.17. IEEE 1149.1-Compliant Boundary Scan Testability	44
2.18. Device Configuration	45
2.18.1. Enhanced Configuration Options	45
2.18.2. Single Event Upset (SEU) Support	45
2.18.3. On-Chip Oscillator	46
2.19. Density Shifting	46
3. DC and Switching Characteristics	47

3.1.	Absolute Maximum Ratings	47
3.2.	Recommended Operating Conditions	47
3.3.	Power Supply Ramp Rates.....	48
3.4.	Power-On-Reset Voltage Levels	48
3.5.	Power up Sequence.....	48
3.6.	Hot Socketing Specifications	48
3.7.	Hot Socketing Requirements.....	49
3.8.	ESD Performance.....	49
3.9.	DC Electrical Characteristics	49
3.10.	Supply Current (Standby)	50
3.11.	SERDES Power Supply Requirements ^{1,2,3}	51
3.12.	sysI/O Recommended Operating Conditions	53
3.13.	sysI/O Single-Ended DC Electrical Characteristics	54
3.14.	sysI/O Differential Electrical Characteristics	55
3.14.1.	LVDS.....	55
3.14.2.	SSTLD	55
3.14.3.	LVC MOS33D.....	55
3.14.4.	LVDS25E.....	56
3.14.5.	BLVDS25.....	57
3.14.6.	LVPECL33	58
3.14.7.	MLVDS25	59
3.14.8.	SLVS	60
3.15.	Typical Building Block Function Performance	61
3.16.	Derating Timing Tables.....	62
3.17.	Maximum I/O Buffer Speed	63
3.18.	External Switching Characteristics	64
3.19.	sysCLOCK PLL Timing.....	71
3.20.	SERDES High-Speed Data Transmitter.....	72
3.21.	SERDES/PCS Block Latency	73
3.22.	SERDES High-Speed Data Receiver	74
3.23.	Input Data Jitter Tolerance.....	74
3.24.	SERDES External Reference Clock.....	75
3.25.	PCI Express Electrical and Timing Characteristics.....	76
3.25.1.	PCIe (2.5 Gb/s) AC and DC Characteristics.....	76
3.25.2.	PCIe (5 Gb/s) – Preliminary AC and DC Characteristics	77
3.26.	CPRI LV2 E.48 Electrical and Timing Characteristics – Preliminary.....	79
3.27.	XAUI/CPRI LV E.30 Electrical and Timing Characteristics	80
3.27.1.	AC and DC Characteristics	80
3.28.	CPRI LV E.24/SGMII(2.5Gbps) Electrical and Timing Characteristics	80
3.28.1.	AC and DC Characteristics	80
3.29.	Gigabit Ethernet/SGMII(1.25Gbps)/CPRI LV E.12 Electrical and Timing Characteristics	81
3.29.1.	AC and DC Characteristics	81
3.30.	SMPTE SD/HD-SDI/3G-SDI (Serial Digital Interface) Electrical and Timing Characteristics	82
3.30.1.	AC and DC Characteristics	82
3.31.	sysCONFIG Port Timing Specifications	83
3.32.	JTAG Port Timing Specifications	88
3.33.	Switching Test Conditions	89
4.	Pinout Information	91
4.1.	Signal Descriptions	91
4.2.	PICs and DDR Data (DQ) Pins Associated with the DDR Strobe (DQS) Pin	94
4.3.	Pin Information Summary	94
4.3.1.	LFESUM/LFESUM5G	94
4.3.2.	LFESU	96
5.	Ordering Information.....	97

5.1.	ECP5/ECP5-5G Part Number Description	97
5.2.	Ordering Part Numbers	98
5.2.1.	Commercial	98
5.2.2.	Industrial	100
	Supplemental Information	102
	For Further Information	102
	Revision History	103

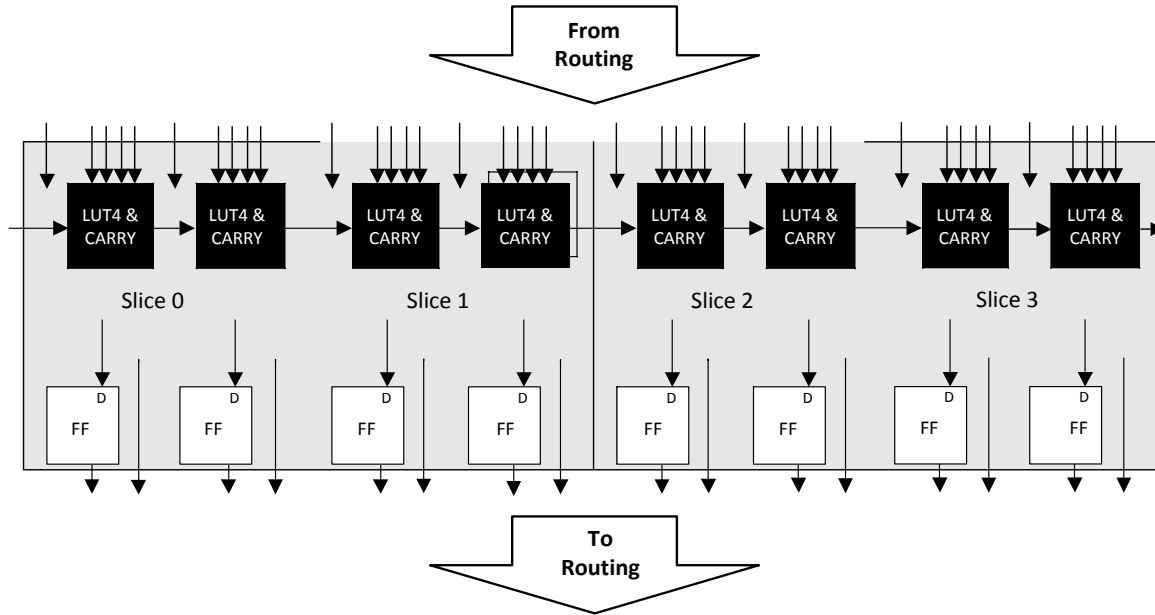


Figure 2.2. PFU Diagram

2.2.1. Slice

Each slice contains two LUT4s feeding two registers. In Distributed SRAM mode, Slice 0 through Slice 2 are configured as distributed memory, and Slice 3 is used as Logic or ROM. Table 2.1 shows the capability of the slices along with the operation modes they enable. In addition, each PFU contains logic that allows the LUTs to be combined to perform functions such as LUT5, LUT6, LUT7 and LUT8. There is control logic to perform set/reset functions (programmable as synchronous/ asynchronous), clock select, chip-select and wider RAM/ROM functions.

Table 2.1. Resources and Modes Available per Slice

Slice	PFU (Used in Distributed SRAM)		PFU (Not used as Distributed SRAM)	
	Resources	Modes	Resources	Modes
Slice 0	2 LUT4s and 2 Registers	RAM	2 LUT4s and 2 Registers	Logic, Ripple, ROM
Slice 1	2 LUT4s and 2 Registers	RAM	2 LUT4s and 2 Registers	Logic, Ripple, ROM
Slice 2	2 LUT4s and 2 Registers	RAM	2 LUT4s and 2 Registers	Logic, Ripple, ROM
Slice 3	2 LUT4s and 2 Registers	Logic, Ripple, ROM	2 LUT4s and 2 Registers	Logic, Ripple, ROM

Figure 2.3 shows an overview of the internal logic of the slice. The registers in the slice can be configured for positive/negative and edge triggered or level sensitive clocks.

Each slice has 14 input signals, 13 signals from routing and one from the carry-chain (from the adjacent slice or PFU). There are five outputs, four to routing and one to carry-chain (to the adjacent PFU). There are two inter slice/ PFU output signals that are used to support wider LUT functions, such as LUT6, LUT7 and LUT8. Table 2.2 and Figure 2.3 list the signals associated with all the slices. Figure 2.4 on page 16 shows the connectivity of the inter-slice/PFU signals that support LUT5, LUT6, LUT7 and LUT8.

2.3. Routing

There are many resources provided in the ECP5/ECP5-5G devices to route signals individually or as busses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments. The ECP5/ECP5-5G family has an enhanced routing architecture that produces a compact design. The Diamond design software tool suites take the output of the synthesis tool and places and routes the design.

2.4. Clocking Structure

ECP5/ECP5-5G clocking structure consists of clock synthesis blocks (sysCLOCK PLL); balanced clock tree networks (PCLK and ECLK trees); and efficient clock logic modules (CLOCK DIVIDER and Dynamic Clock Select (DCS), Dynamic Clock Control (DCC) and DLL). All of these functions are described below.

2.4.1. sysCLOCK PLL

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The devices in the ECP5/ECP5-5G family support two to four full-featured General Purpose PLLs. The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The architecture of the PLL is shown in Figure 2.5. A description of the PLL functionality follows.

CLKI is the reference frequency input to the PLL and its source can come from two different external CLK inputs or from internal routing. A non-glitchless 2-to-1 input multiplexer is provided to dynamically select between two different external reference clock sources. The CLKI input feeds into the input Clock Divider block.

CLKFB is the feedback signal to the PLL which can come from internal feedback path, routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The PLL has four clock outputs CLKOP, CLKOS, CLKOS2 and CLKOS3. Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the primary clock network. Only CLKOP and CLKOS outputs can go to the edge clock network.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock. This phase shift can be either programmed during configuration or can be adjusted dynamically using the PHASESEL, PHASEDIR, PHASESTEP, and PHASELOADREG ports.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected.

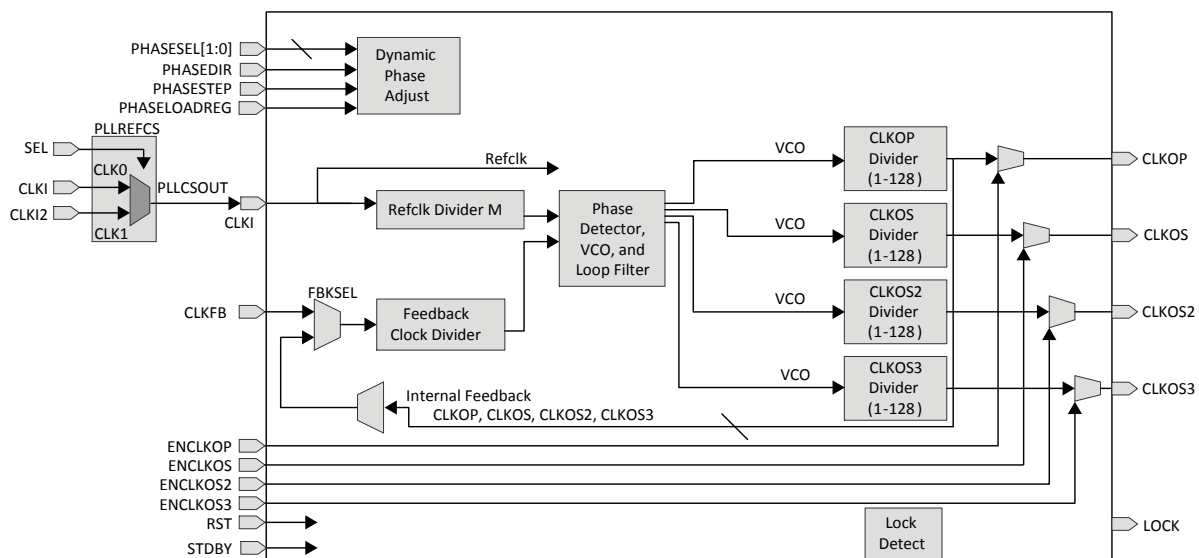


Figure 2.5. General Purpose PLL Diagram

Table 2.4 provides a description of the signals in the PLL blocks.

Table 2.4. PLL Blocks Signal Descriptions

Signal	Type	Description
CLKI	Input	Clock Input to PLL from external pin or routing
CLKI2	Input	Muxed clock input to PLL
SEL	Input	Input Clock select, selecting from CLKI and CLKI2 inputs
CLKFB	Input	PLL Feedback Clock
PHASESEL[1:0]	Input	Select which output to be adjusted on Phase by PHASEDIR, PHASESTEP, PHASELOADREG
PHASEDIR	Input	Dynamic Phase adjustment direction.
PHASESTEP	Input	Dynamic Phase adjustment step.
PHASELOADREG	Input	Load dynamic phase adjustment values into PLL.
CLKOP	Output	Primary PLL output clock (with phase shift adjustment)
CLKOS	Output	Secondary PLL output clock (with phase shift adjust)
CLKOS2	Output	Secondary PLL output clock2 (with phase shift adjust)
CLKOS3	Output	Secondary PLL output clock3 (with phase shift adjust)
LOCK	Output	PLL LOCK to CLKI, Asynchronous signal. Active high indicates PLL lock
STDBY	Input	Standby signal to power down the PLL
RST	Input	Resets the PLL
ENCLKOP	Input	Enable PLL output CLKOP
ENCLKOS	Input	Enable PLL output CLKOS
ENCLKOS2	Input	Enable PLL output CLKOS2
ENCLKOS3	Input	Enable PLL output CLKOS3

For more details on the PLL you can refer to the [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#).

2.5. Clock Distribution Network

There are two main clock distribution networks for any member of the ECP5/ECP5-5G product family, namely Primary Clock (PCLK) and Edge Clock (ECLK). These clock networks have the clock sources come from many different sources, such as Clock Pins, PLL outputs, DLLDEL outputs, Clock divider outputs, SERDES/PCS clocks and some on chip generated clock signal. There are clock dividers (CLKDIV) blocks to provide the slower clock from these clock sources. ECP5/ECP5-5G also supports glitchless dynamic enable function (DCC) for the PCLK Clock to save dynamic power. There are also some logics to allow dynamic glitchless selection between two clocks for the PCLK network (DCS).

Overview of Clocking Network is shown in [Figure 2.6](#) on page 20 for LFE5UM/LFE5UM5G-85 device.

2.11. PIO

The PIO contains three blocks: an input register block, output register block, and tristate register block. These blocks contain registers for operating in a variety of modes along with the necessary clock and selection logic.

2.11.1. Input Register Block

The input register blocks for the PIOs on all edges contain delay elements and registers that can be used to condition high-speed interface signals before they are passed to the device core. In addition, the input register blocks for the PIOs on the left and right edges include built-in FIFO logic to interface to DDR and LPDDR memory.

The Input register block on the right and left sides includes gearing logic and registers to implement IDDRX1 and IDDRX2 functions. With two PICs sharing the DDR register path, it can also implement IDDRX71 function used for 7:1 LVDS interfaces. It uses three sets of registers to shift, update, and transfer to implement gearing and the clock domain transfer. The first stage registers samples the high-speed input data by the high-speed edge clock on its rising and falling edges. The second stage registers perform data alignment based on the control signals. The third stage pipeline registers pass the data to the device core synchronized to the low-speed system clock. The top side of the device supports IDDRX1 gearing function. For more information on gearing function, refer to [ECP5 and ECP5-5G High-Speed I/O Interface \(TN1265\)](#).

Figure 2.17 shows the input register block for the PIOs on the top edge.

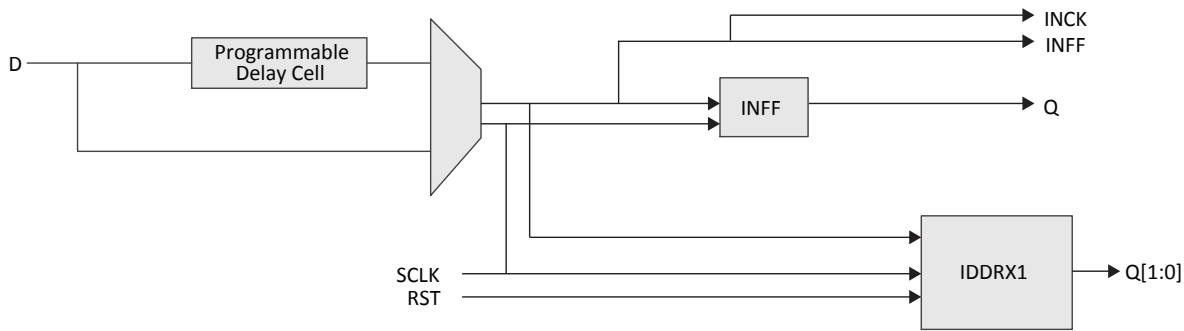
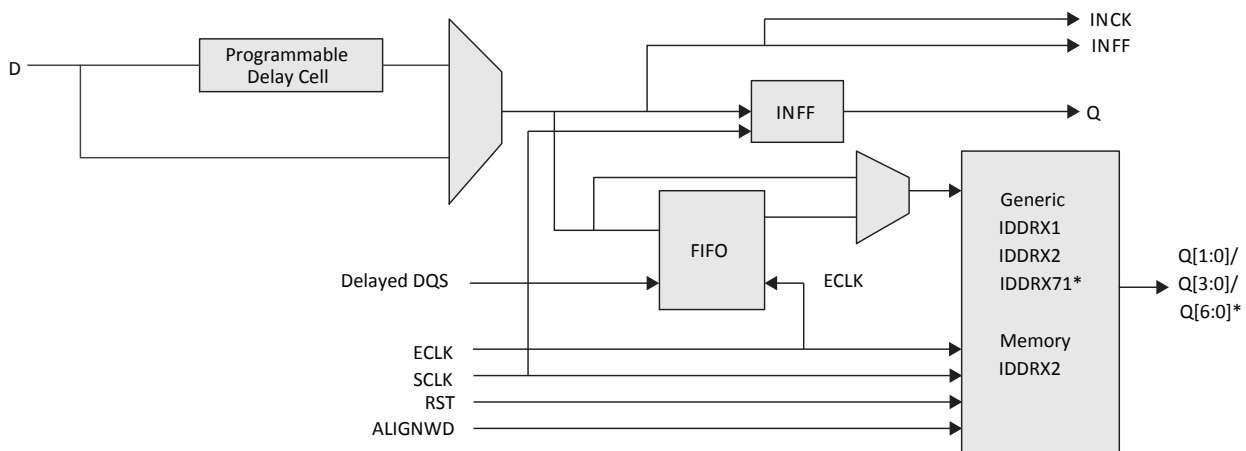


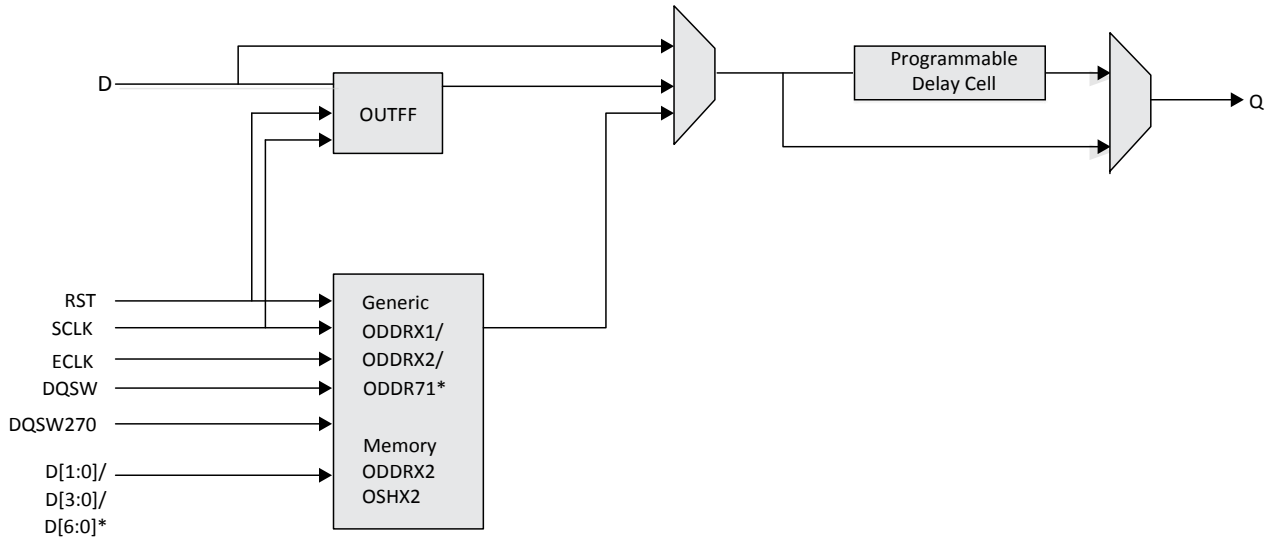
Figure 2.17. Input Register Block for PIO on Top Side of the Device

Figure 2.18 shows the input register block for the PIOs located on the left and right edges.



*For 7:1 LVDS interface only. It is required to use PIO pair pins (PIOA/B or PIOC/D).

Figure 2.18. Input Register Block for PIO on Left and Right Side of the Device



*For 7:1 LVDS interface only. It is required to use PIO pair pins PIOA/B.

Figure 2.20. Output Register Block on Left and Right Sides

Table 2.9. Output Block Port Description

Name	Type	Description
Q	Output	High Speed Data Output
D	Input	Data from core to output SDR register
D[1:0]/D[3:0]/ D[6:0]	Input	Low Speed Data from device core to output DDR register
RST	Input	Reset to the Output Block
SCLK	Input	Slow Speed System Clock
ECLK	Input	High Speed Edge Clock
DQSW	Input	Clock from DQS control Block used to generate DDR memory DQS output
DQSW270	Input	Clock from DQS control Block used to generate DDR memory DQ output

2.12. Tristate Register Block

The tristate register block registers tristate control signals from the core of the device before they are passed to the sysIO buffers. The block contains a register for SDR operation. In SDR, TD input feeds one of the flip-flops that then feeds the output. In DDR operation used mainly for DDR memory interface can be implemented on the left and right sides of the device. Here two inputs feed the tristate registers clocked by both ECLK and SCLK.

Figure 2.21 and Figure 2.22 show the Tristate Register Block functions on the device. For detailed description of the tristate register block modes and usage, refer to [ECP5 and ECP5-5G High-Speed I/O Interface \(TN1265\)](#).

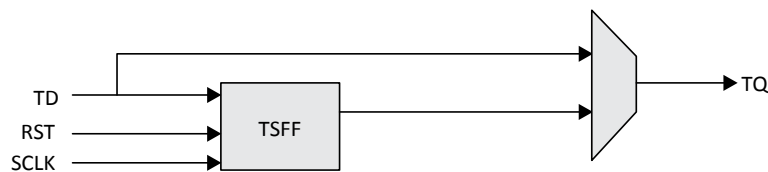


Figure 2.21. Tristate Register Block on Top Side

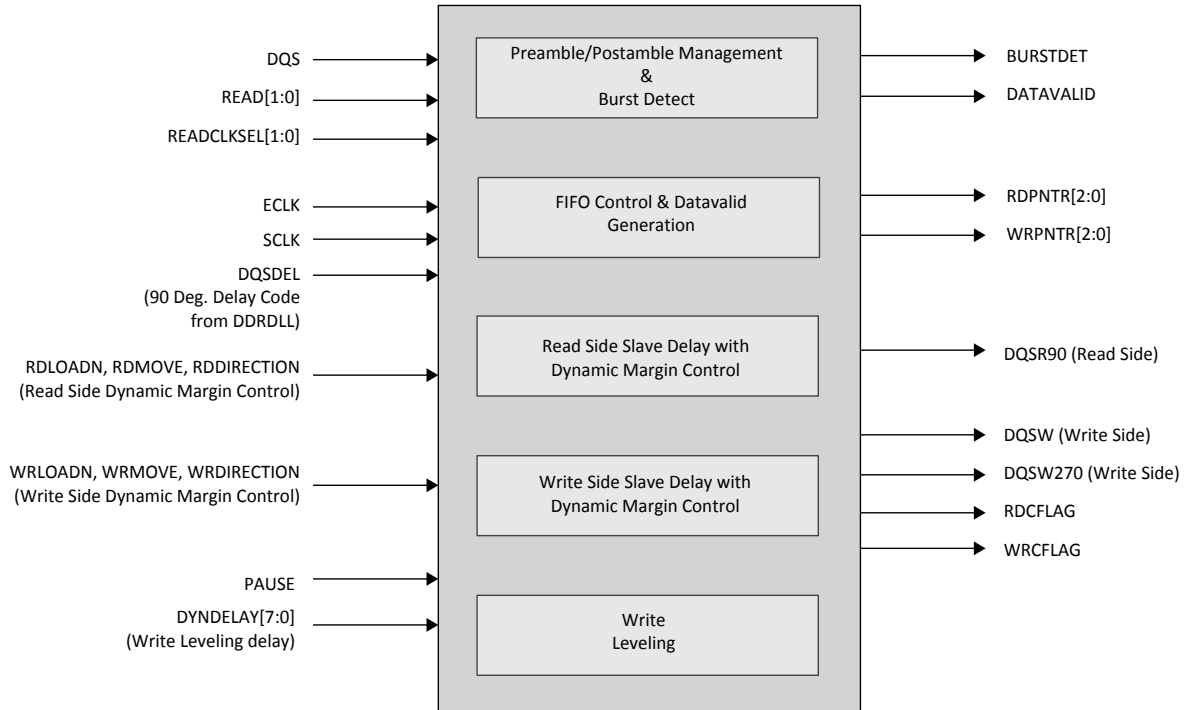


Figure 2.24. DQS Control and Delay Block (DQSBUF)

Table 2.11. DQSBUF Port List Description

Name	Type	Description
DQS	Input	DDR memory DQS strobe
READ[1:0]	Input	Read Input from DDR Controller
READCLKSEL[1:0]	Input	Read pulse selection
SCLK	Input	Slow System Clock
ECLK	Input	High Speed Edge Clock (same frequency as DDR memory)
DQSDEL	Input	90° Delay Code from DDRDLL
RDLOADN, RDMOVE, RDDIRECTION	Input	Dynamic Margin Control ports for Read delay
WRLOADN, WRMOVE, WRDIRECTION	Input	Dynamic Margin Control ports for Write delay
PAUSE	Input	Used by DDR Controller to Pause write side signals during DDRDLL Code update or Write Leveling
DYNDELAY[7:0]	Input	Dynamic Write Leveling Delay Control
DQSR90	Output	90° delay DQS used for Read
DQSW270	Output	90° delay clock used for DQ Write
DQSW	Output	Clock used for DQS Write
RDPNTR[2:0]	Output	Read Pointer for IFIFO module
WRPNTR[2:0]	Output	Write Pointer for IFIFO module
DATAVALID	Output	Signal indicating start of valid data
BURSTDET	Output	Burst Detect indicator
RDFLAG	Output	Read Dynamic Margin Control output to indicate max value
WRFLAG	Output	Write Dynamic Margin Control output to indicate max value

ECP5/ECP5-5G devices contain two types of sysI/O buffer pairs:

- Top (Bank 0 and Bank 1) and Bottom (Bank 8 and Bank 4) sysI/O Buffer Pairs (Single-Ended Only)

The sysI/O buffers in the Banks at top and bottom of the device consist of ratioed single-ended output drivers and single-ended input buffers. The I/Os in these banks are not usually used as a pair, except when used as emulated differential output pair. They are used as individual I/Os and be configured as different I/O modes, as long as they are compatible with the V_{CCIO} voltage in the bank. When used as emulated differential outputs, the pair can be used together.

The top and bottom side IOs also support hot socketing. They support IO standards from 3.3 V to 1.2 V. They are ideal for general purpose I/Os, or as ADDR/CMD bus for DDR2/DDR3 applications, or for used as emulated differential signaling.

Bank 4 I/O only exists in the LFE5-85 device.

Bank 8 is a bottom bank that shares with sysConfig I/Os. During configuration, these I/Os are used for programming the device. Once the configuration is completed, these I/Os can be released and user can use these I/Os for functional signals in his design.

The top and bottom side pads can be identified by the Lattice Diamond tool.

- Left and Right (Banks 2, 3, 6 and 7) sysI/O Buffer Pairs (50% Differential and 100% Single-Ended Outputs)

The sysI/O buffer pairs in the left and right banks of the device consist of two single-ended output drivers, two single-ended input buffers (both ratioed and referenced) and half of the sysI/O buffer pairs (PIOA/B pairs) also has a high-speed differential output driver. One of the referenced input buffers can also be configured as a differential input. In these banks the two pads in the pair are described as “true” and “comp”, where the true pad is associated with the positive side of the differential I/O, and the comp (complementary) pad is associated with the negative side of the differential I/O.

In addition, programmable on-chip input termination (parallel or differential, static or dynamic) is supported on these sides, which is required for DDR3 interface. However, there is no support for hot-socketing for the I/O pins located on the left and right side of the device as the PCI clamp is always enabled on these pins.

LVDS differential output drivers are available on 50% of the buffer pairs on the left and right banks.

2.14.2. Typical sysI/O I/O Behavior during Power-up

The internal Power-On-Reset (POR) signal is deactivated when V_{CC} , V_{CCIO8} and V_{CCAUX} have reached satisfactory levels. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user’s responsibility to ensure that all other V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. For more information about controlling the output logic state with valid input logic levels during power-up in ECP5/ECP5-5G devices, see the list of technical documentation in [Supplemental Information](#) section on page 102.

The V_{CC} and V_{CCAUX} supply the power to the FPGA core fabric, whereas the V_{CCIO} supplies power to the I/O buffers. In order to simplify system design while providing consistent and predictable I/O behavior, it is recommended that the I/O buffers be powered-up prior to the FPGA core fabric. V_{CCIO} supplies should be powered-up before or together with the V_{CC} and V_{CCAUX} supplies.

2.14.3. Supported sysI/O Standards

The ECP5/ECP5-5G sysI/O buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTTL and other standards. The buffers support the LVTTTL, LVCMOS 1.2 V, 1.5 V, 1.8 V, 2.5 V and 3.3 V standards. In the LVCMOS and LVTTTL modes, the buffer has individual configuration options for drive strength, slew rates, bus maintenance (weak pull-up, weak pull-down, or a bus-keeper latch) and open drain. Other single-ended standards supported include SSTL and HSUL. Differential standards supported include LVDS, differential SSTL and differential HSUL. For further information on utilizing the sysI/O buffer to support a variety of standards, refer to [ECP5 and ECP5-5G sysI/O Usage Guide \(TN1262\)](#).

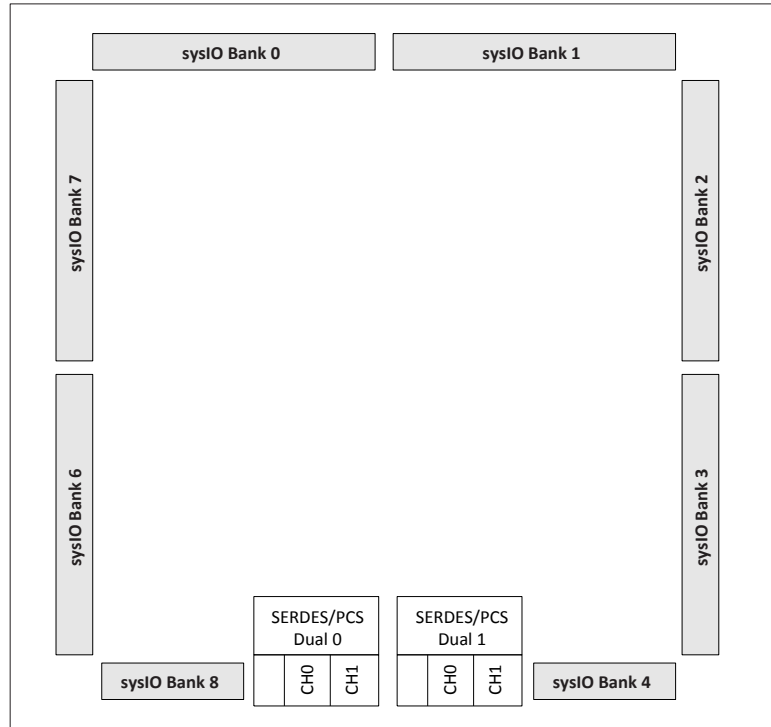


Figure 2.27. SERDES/PCS Duals (LFE5UM/LFE5UM5G-85)

Table 2.13. LFE5UM/LFE5UM5G SERDES Standard Support

Standard	Data Rate (Mb/s)	Number of General/Link Width	Encoding Style
PCI Express 1.1 and 2.0 2.02	2500	x1, x2, x4	8b10b
	5000 ²	x1, x2	8b10b
Gigabit Ethernet	1250	x1	8b10b
SGMII	1250	x1	8b10b
	2500	x1	8b10b
XAUI	3125	x4	8b10b
CPRI-1 CPRI-2 CPRI-3 CPRI-4 CPRI-5	614.4 1228.8 2457.6 3072.0 4915.2 ²	x1	8b10b
SD-SDI (259M, 344M) ¹	270	x1	NRZI/Scrambled
HD-SDI (292M)	1483.5	x1	NRZI/Scrambled
	1485	x1	NRZI/Scrambled
3G-SDI (424M)	2967	x1	NRZI/Scrambled
	2970	x1	NRZI/Scrambled
JESD204A/B	5000	—	—
	3125	x1	8b/10b

Notes:

1. For SD-SDI rate, the SERDES is bypassed and SERDES input signals are directly connected to the FPGA routing.
2. For ECP5-5G family devices only.

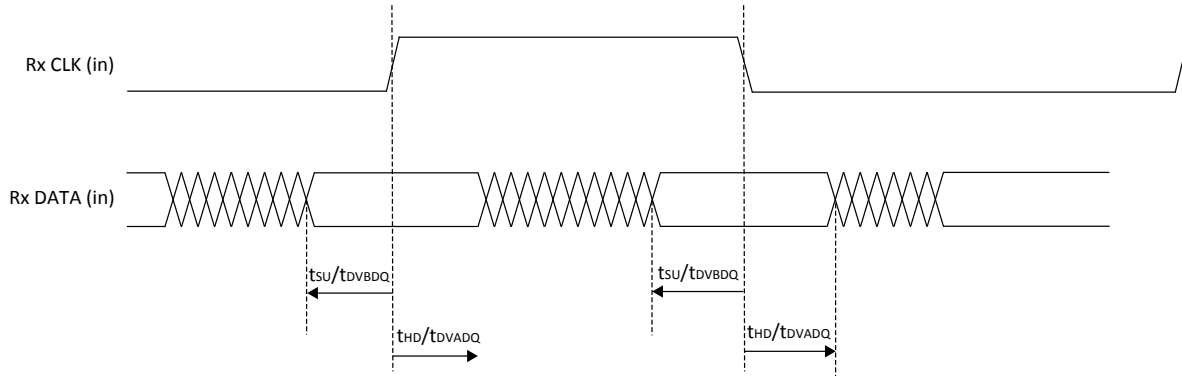


Figure 3.6. Receiver RX.CLK.Centered Waveforms

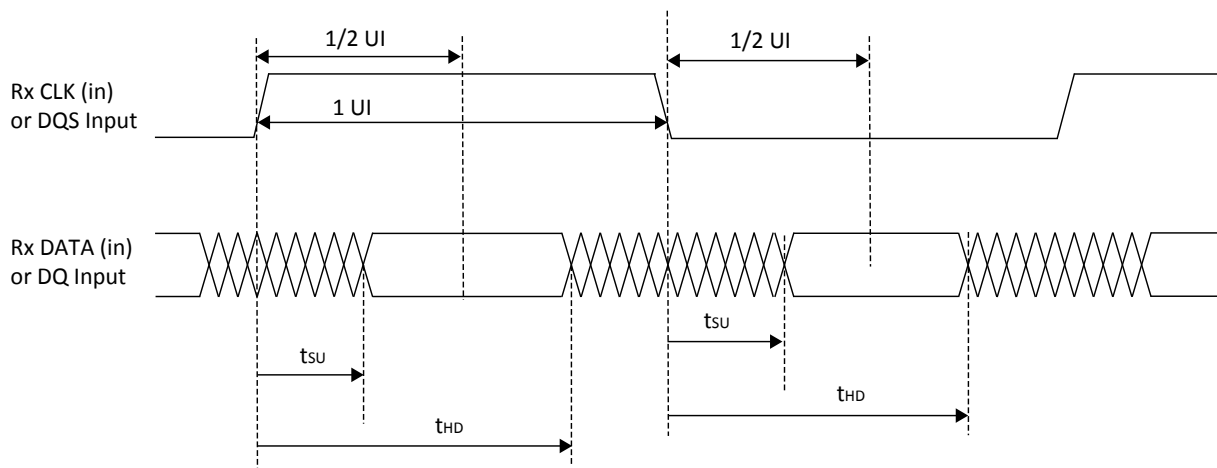


Figure 3.7. Receiver RX.CLK.Aligned and DDR Memory Input Waveforms

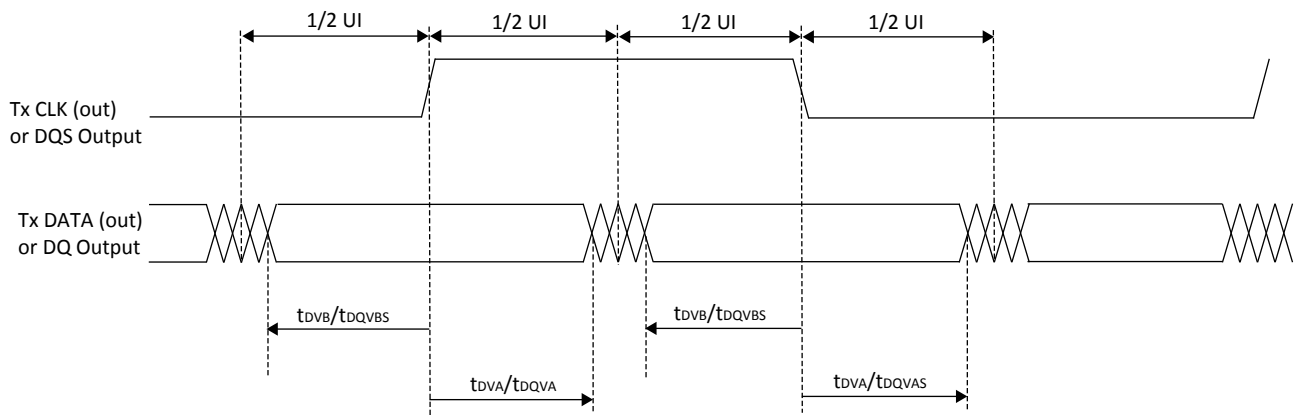


Figure 3.8. Transmit TX.CLK.Centered and DDR Memory Output Waveforms

3.22. SERDES High-Speed Data Receiver

Table 3.27. Serial Input Data Specifications

Symbol	Description	Min	Typ	Max	Unit
V _{RX-DIFF-S}	Differential input sensitivity	150	—	1760	mV, p-p
V _{RX-IN}	Input levels	0	—	V _{CCA} +0.5 ²	V
V _{RX-CM-DCCM}	Input common mode range (internal DC coupled mode)	0.6	—	V _{CCA}	V
V _{RX-CM-ACCM}	Input common mode range (internal AC coupled mode) ²	0.1	—	V _{CCA} +0.2	V
T _{RX-RELOCK}	SCDR re-lock time ¹	—	1000	—	Bits
Z _{RX-TERM}	Input termination 50/75 Ω /High Z	-20%	50/75/5 K	+20%	Ω
RL _{RX-RL}	Return loss (without package)	—	—	-10	dB

Notes:

1. This is the typical number of bit times to re-lock to a new phase or frequency within ±300 ppm, assuming 8b10b encoded data.
2. Up to 1.655 for ECP5, and 1.76 for ECP5-5G.

3.23. Input Data Jitter Tolerance

A receiver’s ability to tolerate incoming signal jitter is very dependent on jitter type. High speed serial interface standards have recognized the dependency on jitter type and have specifications to indicate tolerance levels for different jitter types as they relate to specific protocols. Sinusoidal jitter is considered to be a worst case jitter type.

Table 3.28. Receiver Total Jitter Tolerance Specification

Description	Frequency	Condition	Min	Typ	Max	Unit
Deterministic	5 Gb/s	400 mV differential eye	—	—	TBD	UI, p-p
Random		400 mV differential eye	—	—	TBD	UI, p-p
Total		400 mV differential eye	—	—	TBD	UI, p-p
Deterministic	3.125 Gb/s	400 mV differential eye	—	—	0.37	UI, p-p
Random		400 mV differential eye	—	—	0.18	UI, p-p
Total		400 mV differential eye	—	—	0.65	UI, p-p
Deterministic	2.5 Gb/s	400 mV differential eye	—	—	0.37	UI, p-p
Random		400 mV differential eye	—	—	0.18	UI, p-p
Total		400 mV differential eye	—	—	0.65	UI, p-p
Deterministic	1.25 Gb/s	400 mV differential eye	—	—	0.37	UI, p-p
Random		400 mV differential eye	—	—	0.18	UI, p-p
Total		400 mV differential eye	—	—	0.65	UI, p-p

Notes:

1. Jitter tolerance measurements are done with protocol compliance tests: 3.125 Gb/s - XAUI Standard, 2.5 Gb/s - PCIe Standard, 1.25 Gb/s - SGMII Standard.
2. For ECP5-5G family devices only.

3.26. CPRI LV2 E.48 Electrical and Timing Characteristics – Preliminary

Table 3.32. CPRI LV2 E.48 Electrical and Timing Characteristics

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
Transmit						
UI	Unit Interval	—	203.43	203.45	203.47	ps
T _{DCD}	Duty Cycle Distortion	—	—	—	0.05	UI
J _{UBHPJ}	Uncorrelated Bounded High Probability Jitter	—	—	—	0.15	UI
J _{TOTAL}	Total Jitter	—	—	—	0.3	UI
Z _{RX-DIFF-DC}	DC differential Impedance	—	80	—	120	Ω
T _{SKEW}	Skew between differential signals	—	—	—	9	ps
R _{LTX-DIFF}	Tx Differential Return Loss (S22), including package and silicon	100 MHz < freq < 3.6864 GHz	—	—	–8	dB
		3.6864 GHz < freq < 4.9152 GHz	—	—	–8 + 16.6 *log (freq/3.6864)	dB
R _{LTX-CM}	Tx Common Mode Return Loss, including package and silicon	100 MHz < freq < 3.6864 GHz	6	—	—	dB
I _{TX-SHORT}	Transmitter short-circuit current	—	—	—	100	mA
T _{RISE_FALL-DIFF}	Differential Rise and Fall Time	—	—	—	—	ps
L _{TX-SKEW}	Lane-to-lane output skew	—	—	—	—	ps
Receive						
UI	Unit Interval	—	203.43	203.45	203.47	ps
V _{RX-DIFF-PP}	Differential Rx peak-peak voltage	—	—	—	1.2	V, p-p
V _{RX-EYE_Y1_Y2}	Receiver eye opening mask, Y1 and Y2	—	62.5	—	375	mV, diff
V _{RX-EYE_X1}	Receiver eye opening mask, X1	—	—	—	0.3	UI
T _{RX-TJ}	Receiver total jitter tolerance (not including sinusoidal)	—	—	—	0.6	UI
R _{LRX-DIFF}	Receiver differential Return Loss, package plus silicon	100 MHz < freq < 3.6864 GHz	—	—	–8	dB
		3.6864 GHz < freq < 4.9152 GHz	—	—	–8 + 16.6 *log (freq/3.6864)	dB
R _{LRX-CM}	Receiver common mode Return Loss, package plus silicon	—	6	—	—	dB
Z _{RX-DIFF-DC}	Receiver DC differential impedance	—	80	100	120	Ω

Note: Data is measured with PRBS7 data pattern, not with PRBS-31 pattern.

3.31. sysCONFIG Port Timing Specifications

Over recommended operating conditions.

Table 3.42. ECP5/ECP5-5G sysCONFIG Port Timing Specifications

Symbol	Parameter		Min	Max	Unit
POR, Configuration Initialization, and Wakeup					
t_{ICFG}	Time from the Application of V_{CC} , V_{CCAUX} or V_{CCIO8} (whichever is the last) to the rising edge of INITN	—	—	33	ms
t_{VMC}	Time from t_{ICFG} to the valid Master CCLK	—	—	5	us
t_{CZ}	CCLK from Active to High-Z	—	—	300	ns
Master CCLK					
f_{MCLK}	Frequency	All selected frequencies	-20	20	%
$t_{MCLK-DC}$	Duty Cycle	All selected frequencies	40	60	%
All Configuration Modes					
t_{PRGM}	PROGRAMN LOW pulse accepted	—	110	—	ns
t_{PRGMRJ}	PROGRAMN LOW pulse rejected	—	—	50	ns
t_{INITL}	INITN LOW time	—	—	55	ns
t_{DPPINT}	PROGRAMN LOW to INITN LOW	—	—	70	ns
$t_{DPPDONE}$	PROGRAMN LOW to DONE LOW	—	—	80	ns
t_{IODISS}	PROGRAMN LOW to I/O Disabled	—	—	150	ns
Slave SPI					
f_{CCLK}	CCLK input clock frequency	—	—	60	MHz
t_{CCLKH}	CCLK input clock pulsewidth HIGH	—	6	—	ns
t_{CCLKL}	CCLK input clock pulsewidth LOW	—	6	—	ns
t_{STSU}	CCLK setup time	—	1	—	ns
t_{STH}	CCLK hold time	—	1	—	ns
t_{STCO}	CCLK falling edge to valid output	—	—	10	ns
t_{STOZ}	CCLK falling edge to valid disable	—	—	10	ns
t_{STOV}	CCLK falling edge to valid enable	—	—	10	ns
t_{SCS}	Chip Select HIGH time	—	25	—	ns
t_{SCSS}	Chip Select setup time	—	3	—	ns
t_{SCSH}	Chip Select hold time	—	3	—	ns
Master SPI					
f_{CCLK}	Max selected CCLK output frequency	—	—	62	MHz
t_{CCLKH}	CCLK output clock pulse width HIGH	—	3.5	—	ns
t_{CCLKL}	CCLK output clock pulse width LOW	—	3.5	—	ns
t_{STSU}	CCLK setup time	—	5	—	ns
t_{STH}	CCLK hold time	—	1	—	ns
t_{CSSPI}	INITN HIGH to Chip Select LOW	—	100	200	ns
t_{CFGX}	INITN HIGH to first CCLK edge	—	—	150	ns
Slave Serial					
f_{CCLK}	CCLK input clock frequency	—	—	66	MHz
t_{SSCH}	CCLK input clock pulse width HIGH	—	5	—	ns
t_{SSCL}	CCLK input clock pulse width LOW	—	5	—	ns
t_{SUSCDI}	CCLK setup time	—	0.5	—	ns
$t_{HS CDI}$	CCLK hold time	—	1.5	—	ns

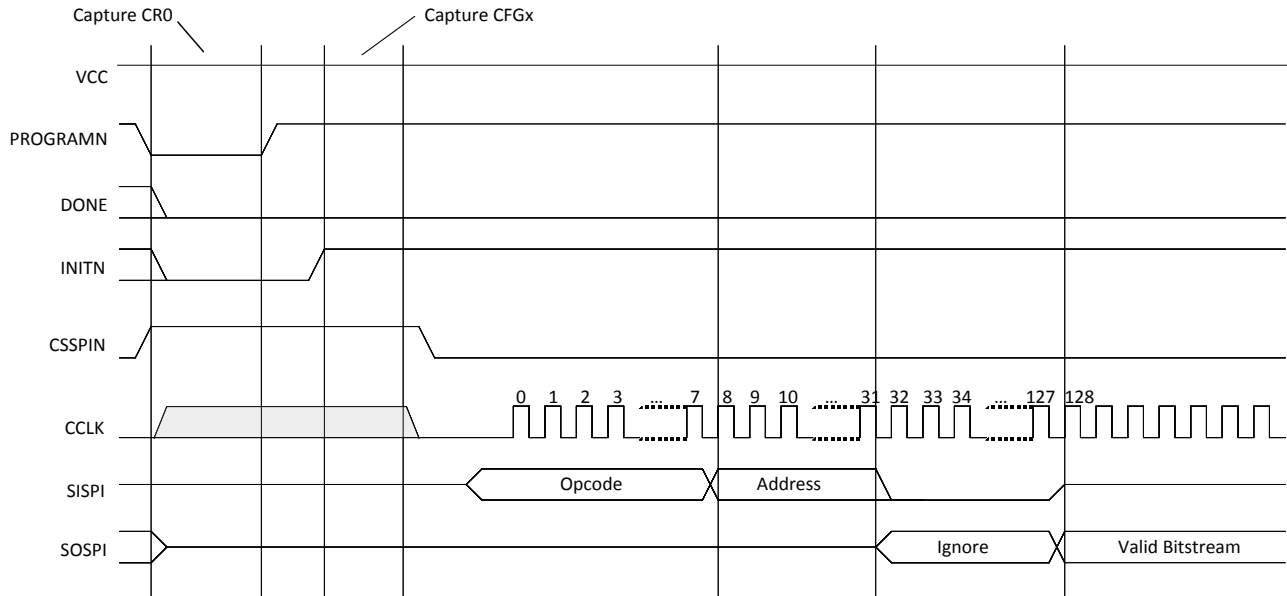


Figure 3.22. Master SPI Configuration Waveforms

3.32. JTAG Port Timing Specifications

Over recommended operating conditions.

Table 3.43. JTAG Port Timing Specifications

Symbol	Parameter	Min	Max	Units
f_{MAX}	TCK clock frequency	—	25	MHz
t_{BTCPH}	TCK [BSCAN] clock pulse width high	20	—	ns
t_{BTCPL}	TCK [BSCAN] clock pulse width low	20	—	ns
t_{BTS}	TCK [BSCAN] setup time	10	—	ns
t_{BTH}	TCK [BSCAN] hold time	8	—	ns
t_{BTRF}	TCK [BSCAN] rise/fall time	50	—	mV/ns
t_{BTCO}	TAP controller falling edge of clock to valid output	—	10	ns
$t_{BTCODIS}$	TAP controller falling edge of clock to valid disable	—	10	ns
t_{BTCOEN}	TAP controller falling edge of clock to valid enable	—	10	ns
t_{BTCRS}	BSCAN test capture register setup time	8	—	ns
t_{BTCRH}	BSCAN test capture register hold time	25	—	ns
t_{BUTCO}	BSCAN test update register, falling edge of clock to valid output	—	25	ns
$t_{BTUODIS}$	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
$t_{BTUPOEN}$	BSCAN test update register, falling edge of clock to valid enable	—	25	ns

Signal Name	I/O	Description
PLL, DLL and Clock Functions (Continued)		
[L/R]DQS[group_num]	I/O	DQS input/output pads: T (top), R (right), group_num = ball number associated with DQS[T] pin.
[T/R]DQ[group_num]	I/O	DQ input/output pads: T (top), R (right), group_num = ball number associated with DQS[T] pin.
Test and Programming (Dedicated Pins)		
TMS	I	Test Mode Select input, used to control the 1149.1 state machine. Pull-up is enabled during configuration. This is a dedicated input pin.
TCK	I	Test Clock input pin, used to clock the 1149.1 state machine. No pull-up enabled. This is a dedicated input pin.
TDI	I	Test Data in pin. Used to load data into device using 1149.1 state machine. After power-up, this TAP port can be activated for configuration by sending appropriate command. (Note: once a configuration port is selected it is locked. Another configuration port cannot be selected until the power-up sequence). Pull-up is enabled during configuration. This is a dedicated input pin.
TDO	O	Output pin. Test Data Out pin used to shift data out of a device using 1149.1. This is a dedicated output pin.
Configuration Pads (Used during sysCONFIG)		
CFG[2:0]	I	Mode pins used to specify configuration mode values latched on rising edge of INITN. During configuration, a pull-up is enabled. These are dedicated pins.
INITN	I/O	Open Drain pin. Indicates the FPGA is ready to be configured. During configuration, a pull-up is enabled. This is a dedicated pin.
PROGRAMN	I	Initiates configuration sequence when asserted low. This pin always has an active pull-up. This is a dedicated pin.
DONE	I/O	Open Drain pin. Indicates that the configuration sequence is complete, and the startup sequence is in progress. This is a dedicated pin.
CCLK	I/O	Input Configuration Clock for configuring an FPGA in Slave SPI, Serial, and CPU modes. Output Configuration Clock for configuring an FPGA in Master configuration modes (Master SPI, Master Serial). This is a dedicated pin.
HOLDN/DI/BUSY/CSSPIN/CEN	I/O	Parallel configuration mode busy indicator. SPI/SPI _m mode data output. This is a shared I/O pin. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
CSN/SN	I/O	Parallel configuration mode active-low chip select. Slave SPI chip select. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
CS1N	I	Parallel configuration mode active-low chip select. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
WRITEN	I	Write enable for parallel configuration modes. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
DOUT/CSON	O	Serial data output. Chip select output. SPI/SPI _m mode chip select. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.
DO/MOSI/IOO	I/O	Parallel configuration I/O. Open drain during configuration. When in SPI modes, it is an output in Master mode, and input in Slave mode. This is a shared I/O pin. When not in configuration, it can be used as general purpose I/O pin.

Pin Information Summary		LFE5UM/ LFE5UM5G-25		LFE5UM/LFE5UM5G-45			LFE5UM/LFE5UM5G-85			
		285 csfBG	381 caBGA	285 csfBGA	381 caBG	554 caBGA	285 csfBGA	381 caBG	554 caBGA	756 caBGA
TAP		4	4	4	4	4	4	4	4	4
Miscellaneous Dedicated Pins		7	7	7	7	7	7	7	7	7
GND		83	59	83	59	113	83	59	113	166
NC		1	8	1	2	33	1	0	17	29
Reserved		0	2	0	2	4	0	2	4	4
SERDES		14	28	14	28	28	14	28	28	28
VCCA (SERDES)	VCCA0	2	2	2	2	6	2	2	6	8
	VCCA1	0	2	0	2	6	0	2	6	9
VCCAUX (SERDES)	VCCAUXA0	2	2	2	2	2	2	2	2	2
	VCCAUXA1	0	2	0	2	2	0	2	2	2
GNDA (SERDES)		26	26	26	26	49	26	26	49	60
Total Balls		285	381	285	381	554	285	381	554	756
High Speed Differential Input / Output Pairs	Bank 0	0	0	0	0	0	0	0	0	0
	Bank 1	0	0	0	0	0	0	0	0	0
	Bank 2	10/8	16/8	10/8	16/8	16/8	10/8	17/9	16/8	24/12
	Bank 3	14/7	16/8	14/7	16/8	24/12	14/7	16/8	24/12	32/16
	Bank 4	0	0	0	0	0	0	0	0	0
	Bank 6	13/6	16/8	13/6	16/8	24/12	13/6	16/8	24/12	32/16
	Bank 7	8/6	16/8	8/6	16/8	16/8	8/6	16/8	16/8	24/12
	Bank 8	0	0	0	0	0	0	0	0	0
Total High Speed Differential I/O Pairs		45/2	64/32	45/27	64/3	80/40	45/27	65/3	80/40	112/5
DQS Groups (> 11 pins in group)	Bank 0	0	0	0	0	0	0	0	0	0
	Bank 1	0	0	0	0	0	0	0	0	0
	Bank 2	1	2	1	2	2	1	2	2	3
	Bank 3	2	2	2	2	3	2	2	3	4
	Bank 4	0	0	0	0	0	0	0	0	0
	Bank 6	2	2	2	2	3	2	2	3	4
	Bank 7	1	2	1	2	2	1	2	2	3
	Bank 8	0	0	0	0	0	0	0	0	0
Total DQS Groups		6	8	6	8	10	6	8	10	14

Part number	Grade	Package	Pins	Temp.	LUTs (K)	SERDES
LFE5U-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	No
LFE5U-85F-6MG285C	-6	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-7MG285C	-7	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-6BG381C	-6	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-7BG381C	-7	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-8BG381C	-8	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-6BG554C	-6	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-7BG554C	-7	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-8BG554C	-8	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-6BG756C	-6	Lead free caBGA	756	Commercial	84	No
LFE5U-85F-7BG756C	-7	Lead free caBGA	756	Commercial	84	No
LFE5U-85F-8BG756C	-8	Lead free caBGA	756	Commercial	84	No
LFE5UM-25F-6MG285C	-6	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-7MG285C	-7	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-8MG285C	-8	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-6BG381C	-6	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-25F-7BG381C	-7	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-25F-8BG381C	-8	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-45F-6MG285C	-6	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-7MG285C	-7	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-8MG285C	-8	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-6BG381C	-6	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-7BG381C	-7	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-8BG381C	-8	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-6BG554C	-6	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-45F-7BG554C	-7	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-85F-6MG285C	-6	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-7MG285C	-7	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-6BG381C	-6	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-7BG381C	-7	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-8BG381C	-8	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-6BG554C	-6	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-7BG554C	-7	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-8BG554C	-8	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-6BG756C	-6	Lead free caBGA	756	Commercial	84	Yes
LFE5UM-85F-7BG756C	-7	Lead free caBGA	756	Commercial	84	Yes
LFE5UM-85F-8BG756C	-8	Lead free caBGA	756	Commercial	84	Yes
LFE5UM5G-25F-8MG285C	-8	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM5G-25F-8BG381C	-8	Lead free caBGA	381	Commercial	24	Yes
LFE5UM5G-45F-8MG285C	-8	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM5G-45F-8BG381C	-8	Lead free caBGA	381	Commercial	44	Yes
LFE5UM5G-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	Yes
LFE5UM5G-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	Yes

(Continued)

Date	Version	Section	Change Summary
April 2017	1.7	All	Changed document number from DS1044 to FPGA-DS-02012.
		General Description	Updated Features section. Changed “1.1 V core power supply” to “1.1 V core power supply for ECP5, 1.2 V core power supply for ECP5UM5G”.
		Architecture	Updated Overview section. Change “The ECP5/ECP5-5G devices use 1.1 V as their core voltage” to “The ECP5 devices use 1.1V, ECP5UM5G devices use 1.2V as their core voltage”
		DC and Switching Characteristics	Updated Table 3.2. Recommended Operating Conditions Added ECP5-5G on VCC to be 1.2V +/- 5% Added ECP5-5G on VCCA to be 1.2V +/- 3% Updated Table 3.8. ECP5/ECP5-5G Supply Current (Standby) Changed “Core Power Supply Current” for ICC on LFE5UM5G devices Changed “SERDES Power Supply Current (Per Dual)” for ICCA on LFE5UM5G devices Updated Table 3.20. Register-to-Register Performance. Remove “(DDR/SDR)” from DSP Function Changed DSP functions to 225 MHz
		Pinout Information	Update Section 4.1 Signal Description. Revised Vcc Description to “Power supply pins for core logic. Dedicated pins. VCC = 1.1 V (ECP5), 1.2 V (ECP5UM5G)”
February 2016	1.6	All	Changed document status from Preliminary to Final.
		General Description	Updated Features section. Changed “24K to 84K LUTs” to “12K to 84K LUTs”. Added LFE5U-12 column to Table 1.1. ECP5 and ECP5-5G Family Selection Guide.
		DC and Switching Characteristics	Updated Power up Sequence section. Identified typical ICC current for specific devices in Table 3.8. ECP5/ECP5-5G Supply Current (Standby). Updated values in Table 3.9. ECP5. Updated values in Table 3.10. ECP5-5G. Added values to –8 Timing column of Table 3.19. Pin-to-Pin Performance. Added values to –8 Timing column of Table 3.20. Register-to-Register Performance. Changed LFE5-45 to All Devices in Table 3.22. ECP5/ECP5-5G External Switching Characteristics. Added table notes to Table 3.31. PCIe (5 Gb/s). Added table note to Table 3.32. CPRI LV2 E.48 Electrical and Timing Characteristics.
		Pinout Information	Added LFE5U-12 column to the table in LFE5U section.
		Ordering Information	Updated LFE5U in ECP5/ECP5-5G Part Number Description section: added 12 F = 12K LUTs to Logic Capacity. Added LFE5U-12F information to Ordering Part Numbers section.